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Apêndice

A.1 Estudos do complexo $[\text{Ir}(\text{ppy})_3]$

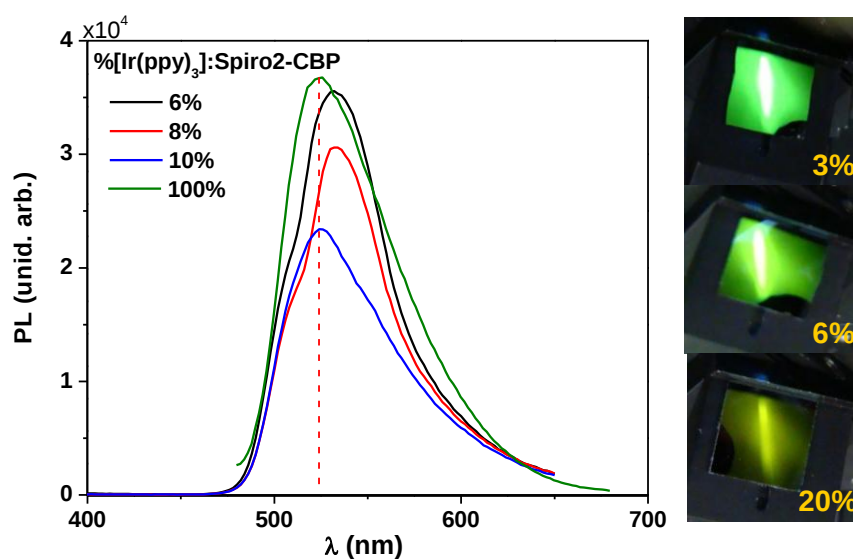


Figura A.1: Espectros de PL do $[\text{Ir}(\text{ppy})_3]$ dopado em Spiro2-CBP com diferentes concentrações em peso e fotos dos filmes de $[\text{Ir}(\text{ppy})_3]$:Spiro2-CBP com três concentrações diferentes de $[\text{Ir}(\text{ppy})_3]$.

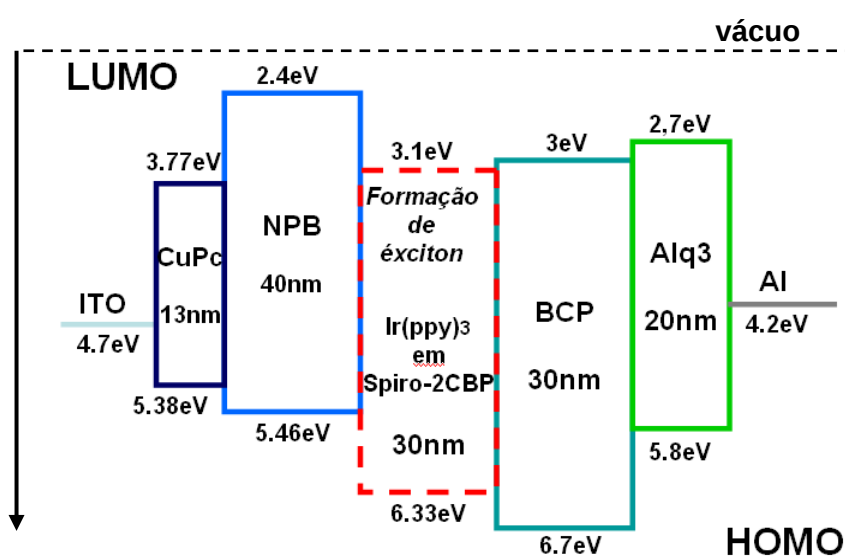


Figura A.2: Estrutura do PHOLED $[\text{Ir}(\text{ppy})_3]$:Spiro2-CBP no diagrama rígido de bandas de energia das diferentes camadas orgânicas. Para os eletrodos (ITO e Al) é indicada a energia da função de trabalho e para os orgânicos os níveis de *HOMO* e *LUMO*.

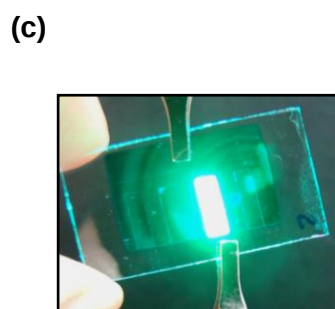
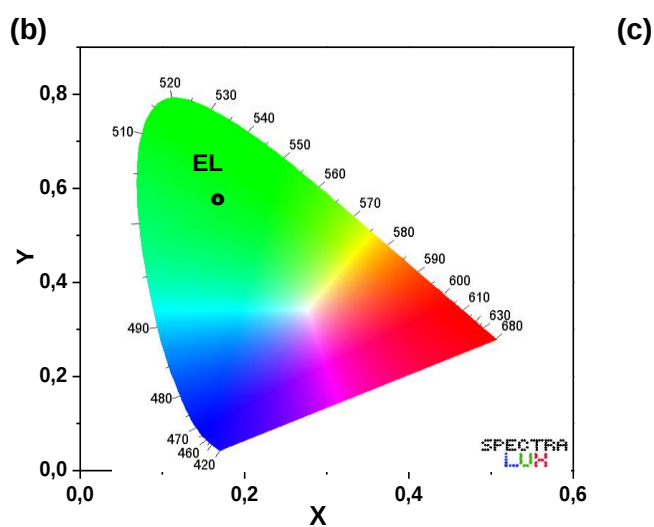
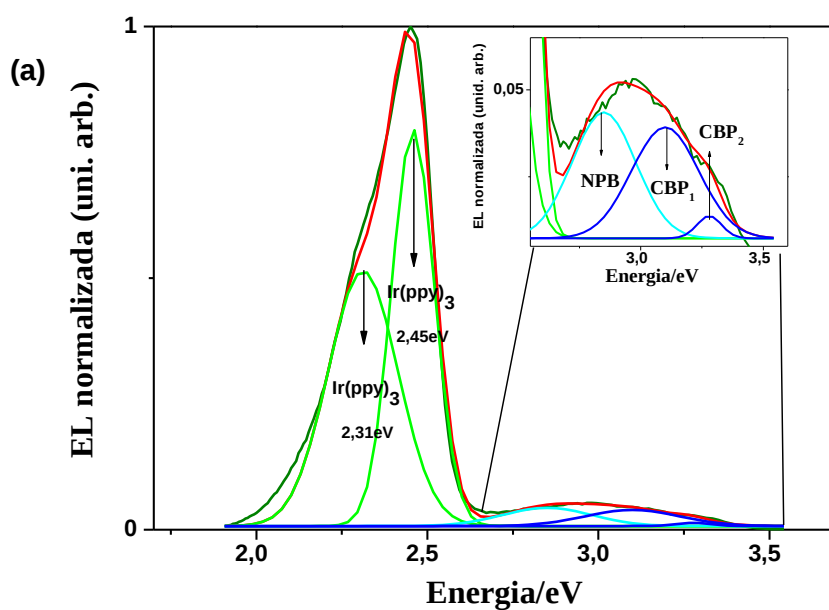


Figura A.3: (a) Espectro de EL, (b) coordenadas de CIE do dispositivo e (c) foto do PHOLED de 6,6% $[\text{Ir}(\text{ppy})_3]$:Spiro2-CBP a 22V de tensão.

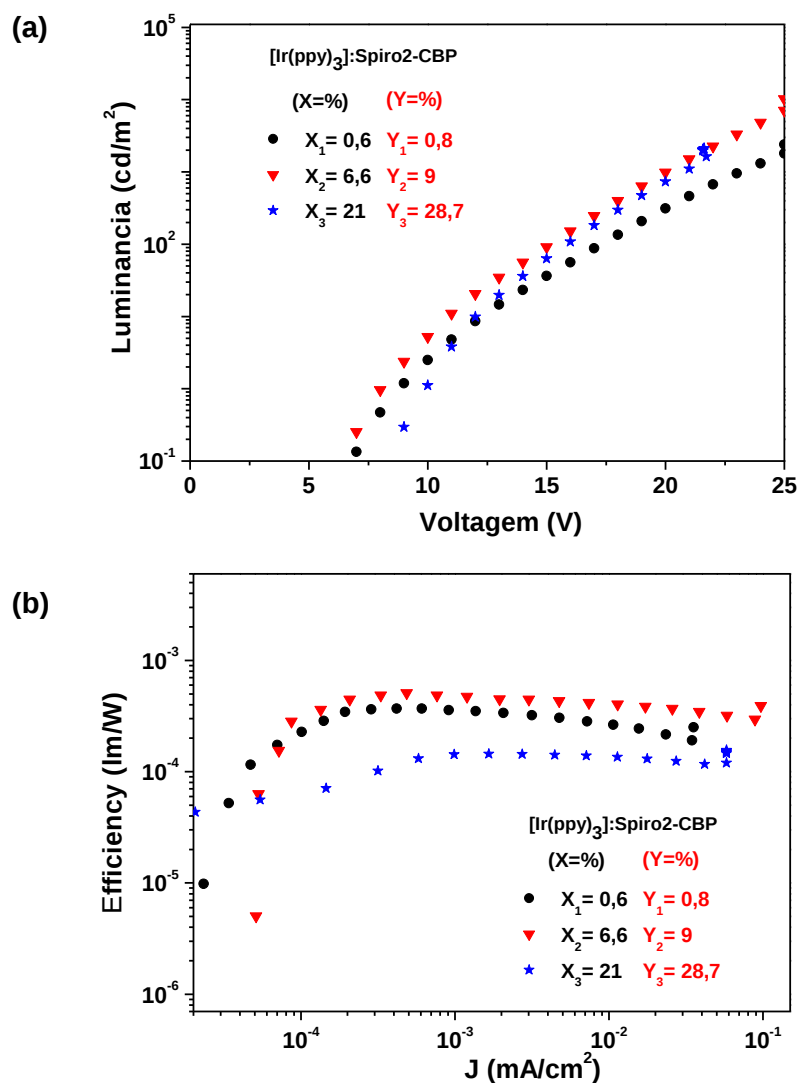


Figura A.4: Curvas de (a) luminância (cd/m²) e (b) eficiência (lm/W) dos *PHOLEDs* com diferentes % em peso do [Ir(ppy)₃] em Spiro2-CBP.